

# AONV070V65GA1

Product Summary at T<sub>1</sub> = 25°C

650 V GaN Enhancement-mode Power Transistor

 $70 \, \text{m}\Omega$ 

8.5nC

94.7nC

60A

0nC

#### **Features**

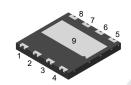
- 650V GaN enhancement-mode transistor
- Normally-off design
- No Qrr (reverse recovery charge)
- Low Qg (gate charge), low Qoss (output charge)
- Integrated ESD protection

## **Applications**

 PFC and PWM stages (LLC, FSFB, TTF) of Server, Telecom, Industrial, UPS, and Solar Inverters

# **Pin Configuration**





 $V_{\text{DS, max}}$ 

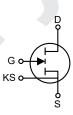
I<sub>D. pulse</sub>

 $R_{DS(on), max} @ V_{GS} = 6V$ 

 $Q_{g, typ} @ V_{DS} = 400 V$ 

 $Q_{oss} @ V_{DS} = 400 V$ 

 $Q_{rr} @ V_{DS} = 400 V$ 



#### **Pin Information**

Gate	Drain	Kelvin Source	Source
5	1, 2, 3, 4	6	7, 8, 9

## **Ordering Information**

Ordering Part Number	Package Type	Form	Shipping Quantity
AONV070V65GA1	DFN8x8	Tape and Reel	1500

#### Contact local sales office for full product datasheet.

#### **Absolute Maximum Ratings**

(T<sub>1</sub> = 25°C, unless otherwise noted)

Symbol		Parameter	AONV070V65GA1	Units	
V <sub>DS, max</sub>	Drain Source Voltage	V <sub>GS</sub> =0V, T <sub>J</sub> =-55°C to 150°C	650		
V <sub>DS, trans</sub>	Drain Source Voltage Transient (1)	V <sub>GS</sub> =0V	800	V	
V	Drain Source Voltage Pulsed (2)	T <sub>C</sub> =25°C, total time < 10 hours	750		
V <sub>DS, pulse</sub>	Dialit Source voltage Fulseu	T <sub>C</sub> =125°C, total time < 1 hour	750		
1	Continuous Drain Current	T <sub>C</sub> =25°C	26	- A	
'D	Continuous Diain Current	T <sub>C</sub> =125°C	17		
1	Pulsed Drain Current (3)	$T_C = 25$ °C, $V_{GS} = 6$ V, $t_{pulse} = 10 \mu s$	60		
D, pulse	Fulsed Drain Current	$T_C = 125$ °C, $V_{GS} = 6$ V, $t_{pulse} = 10 \mu s$	31		
$V_{GS}$	Gate Source Voltage, Continuous (4)	T <sub>J</sub> =-55°C to 150°C	-6 to 7	V	
V <sub>GS, pulse</sub>	Gate Source Voltage, Pulsed	T <sub>J</sub> =-55°C to 150°C, t <sub>pulse</sub> =50ns, f = 100kHz, open drain	-20 to 10	V	
P <sub>tot</sub>	Power Dissipation (5)	Tc=25°C	208	W	
T <sub>j, stg</sub>	Junction and Storage Temperature Range		-55 to 150	°C	



## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Note	Units
$R_{\theta JA}$	Thermal Resistance Junction-to-Ambient (6)	64			°C/W
$R_{\theta JC}$	Thermal Resistance Junction-to-Case	0.50	0.60		°C/W
T <sub>sold</sub>	Maximum Reflow Soldering Temperature	260		MSL3	°C

## **Electrical Characteristics**

(T<sub>\_1</sub> = 25°C, unless otherwise noted)

Symbol	Parameter	Condition	S	Min	Тур	Max	Units	
STATIC PA	STATIC PARAMETERS							
V	Cota Threshold Voltage	\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	T <sub>J</sub> =25°C	1.2	1.7	2.5	V	
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 40 \text{ mA}$	T <sub>J</sub> =150°C		1.6		\ \ \	
1	Drain Source Leakage Current	V 050V/V 0V/	T <sub>J</sub> =25°C		1	65		
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{DS} = 650  \text{V},  V_{GS} = 0  \text{V}$	T <sub>J</sub> =150°C		10		μA	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =6 V, V <sub>DS</sub> =0 V, T <sub>j</sub> =25°C			110		μA	
	Dunin Course On State Besistance		T <sub>J</sub> =25°C		53	70	0	
R <sub>DS(on)</sub>	Drain-Source On-State-Resistance	$V_{GS}=6V$ , $I_D=10A$	$T_{\rm J} = 150^{\circ}{\rm C}$		122		mΩ	
DYNAMIC								
C <sub>iss</sub>	Input Capacitance				300			
Coss	Output Capacitance	V <sub>GS</sub> =0 V, V <sub>DS</sub> =400 V, f=100 kHz			135		pF	
C <sub>rss</sub>	Reverse Transfer Capacitance				2.3		1	
C <sub>o(er)</sub>	Effective Output Capacitance Energy Related (7)	V <sub>GS</sub> =0 V, V <sub>DS</sub> =0 to 400 V			190		pF	
C <sub>o(tr)</sub>	Effective Output Capacitance Time Related (8)				240			
$R_{G}$	Gate Resistance	f=5MHz, open drain			1.4		Ω	
SWITCHIN	G							
Q <sub>q</sub>	Gate Charge				8.5			
Q <sub>gs</sub>	Gate Source Charge	$V_{GS} = 0$ to 6 V, $V_{DS} = 40$	0 V, I <sub>D</sub> = 10 A		0.7		nC	
$Q_{ad}$	Gate Drain Charge				3.6			
V <sub>plat</sub>	Gate Plateau Voltage	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 10 A			2.3		V	
Q <sub>oss</sub>	Output Charge	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 to 400V			94.7		nC	
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DS} = 400 \text{ V}, I_D = 10 \text{ A}, \\ L_{parasitic} = 8 \text{ nH}, V_{GS} = 6 \text{ V}, \\ R_{on} = 10 \Omega, R_{off} = 2 \Omega, L = 350 \mu\text{H}, \\ L_p = 8 \text{nH} \\ \text{FWD: AONV070V65GA1}$			10			
t <sub>d(off)</sub>	Turn-Off Delay Time				7			
t	Rise Time				9		ns	
t <sub>f</sub>	Fall Time				9			

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## **Electrical Characteristics** (Continued)

(T<sub>\_1</sub> = 25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units		
REVERSE (	REVERSE CONDUCTION							
$V_{SD}$	Source-Drain Reverse Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 10 A, T <sub>J</sub> = 25°C		2.4		V		
S, pulse	Reverse Pulsed Current	V <sub>GS</sub> =6V, t <sub>pulse</sub> =10μs			58	Α		
Q <sub>rr</sub>	Reverse Recovery Charge	•		0		nC		
t <sub>rr</sub>	Reverse Recovery Time	$V_R = 400 \text{ V}, I_S = 10 \text{ A}, \text{ dv/dt} = 1 \text{ kA/ } \mu \text{s}$		0		ns		
I <sub>rrm</sub>	Peak Reverse Recovery Current			0		Α		

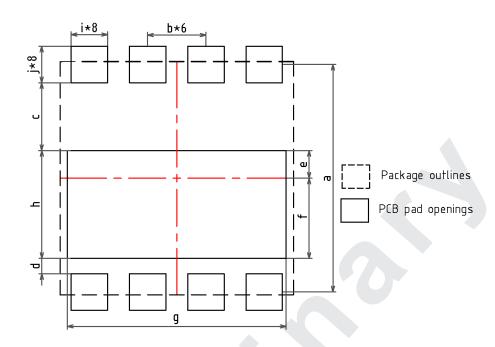
#### Notes:

- 1.  $V_{DS,transient}$  is intended for non-repetitive events,  $t_{PULSE} < 200 \,\mu s$ .
- 2.  $V_{DS,pulse}$  is intended for repetitive pulse,  $t_{PULSE}$  < 100 ns.
- Limit was extracted from characterization test, not measured during production.
- 4. The minimum  $V_{\text{GS}}$  is clamped by ESD protection circuit, as shown in Figure 8.
- 5. Power dissipation, and consequently max. current ratings are obtained using max. thermal resistance and max. temperature of 150 °C.
- R<sub>θJA</sub> is determined with the device mounted on one square inch of copper pad, single layer 2oz copper on FR4 board.
- 7.  $C_{\text{o(er)}}$  is the fixed capacitance that gives the same stored energy as  $C_{\text{OSS}}$  while VDS is rising from 0 to 400 V.
- 8.  $C_{\text{o(tr)}}$  is the fixed capacitance that gives the same charging time as  $C_{\text{OSS}}$  while VDS is rising from 0 to 400 V.

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# **Recommended PCB Footprint**



SYMBOL	DIMENSION	SYMBOL	DIMENSION		
a	7.800	f	2.750		
ь 2.000		g	7.500		
С	2.325	h	3.700		
d	0.525	i	1.400		
е	0.950	j	1.250		

Notes:

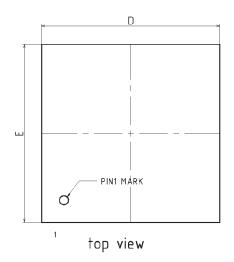
(1) All dimension are in millimeters.

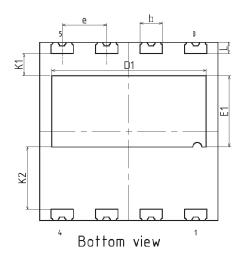
(2)Drawing is not to scale.

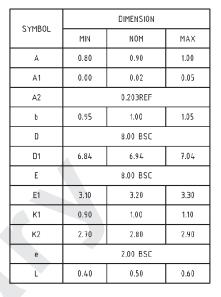
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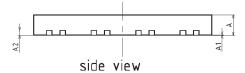


## Package Dimensions, DFN8x8









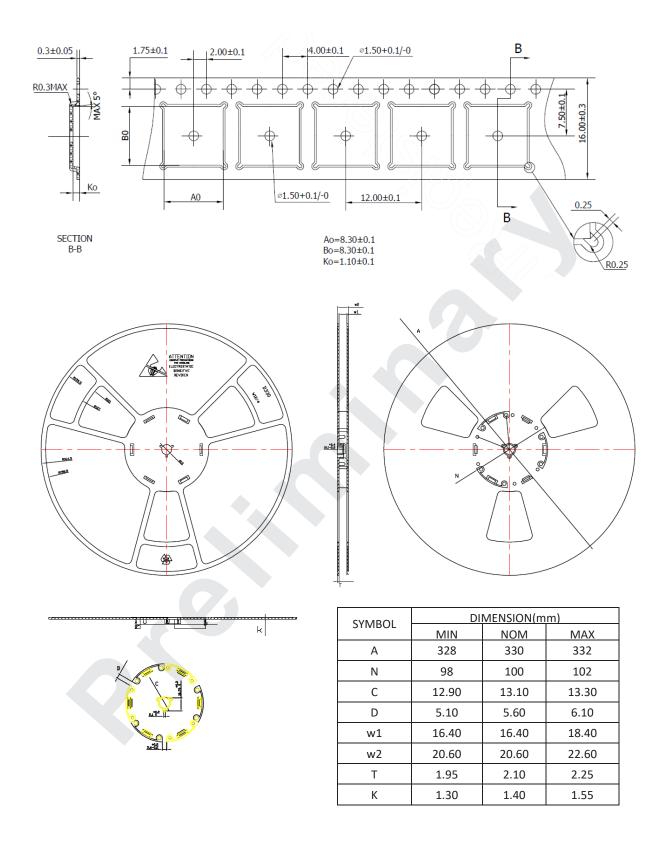
#### Notes:

- 1. Dimension and tolerance conform to ASME Y14.5-2009.
- 2. All dimensions are in millimeters.
- 3. Lead coplanarity will be 0.1 millimeters max.
- 4. Complies with JEDEC MO-229.
- 5. Drawing is not to scale.
- 6. Dimensions do not include mold protrusion.
- 7. Package outline exclusive of metal burr dimensions.

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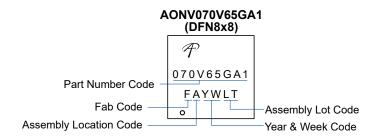


# Tape and Reel Dimensions, DFN8x8





## Part Marking



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